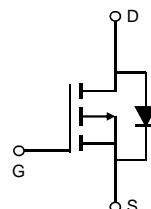


## General Description

The AON2401 combines advanced trench MOSFET technology with a low resistance package to provide extremely low  $R_{DS(ON)}$ . This device is ideal for load switch and battery protection applications.

## Features

$V_{DS}$	-8V
$I_D$ (at $V_{GS}=-2.5V$ )	-8A
$R_{DS(ON)}$ (at $V_{GS}=-2.5V$ )	< 22mΩ
$R_{DS(ON)}$ (at $V_{GS}=-1.8V$ )	< 28mΩ
$R_{DS(ON)}$ (at $V_{GS}=-1.5V$ )	< 36mΩ
$R_{DS(ON)}$ (at $V_{GS}=-1.2V$ )	< 53mΩ



### Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	-8	V
Gate-Source Voltage	$V_{GS}$	$\pm 5$	V
Continuous Drain Current <sup>G</sup>	$I_D$	-8	A
$T_A=70^\circ\text{C}$		-6	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	-32	A
Power Dissipation <sup>A</sup>	$P_D$	2.8	W
$T_A=70^\circ\text{C}$		1.8	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup> $t \leq 10\text{s}$	$R_{\theta JA}$	37	45	°C/W
Maximum Junction-to-Ambient <sup>AD</sup> Steady-State		66	80	°C/W

**Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	I <sub>D</sub> =-250μA, V <sub>GS</sub> =0V	-8			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =-8V, V <sub>GS</sub> =0V T <sub>J</sub> =55°C			-1	μA
I <sub>GSS</sub>	Gate-Body leakage current	V <sub>DS</sub> =0V, V <sub>GS</sub> =±5V			±100	nA
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =-250μA	-0.15	-0.4	-0.65	V
I <sub>D(ON)</sub>	On state drain current	V <sub>GS</sub> =-2.5V, V <sub>DS</sub> =-5V	-32			A
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =-2.5V, I <sub>D</sub> =-8A T <sub>J</sub> =125°C	18	22		mΩ
		V <sub>GS</sub> =-1.8V, I <sub>D</sub> =-6A	24.5	32		mΩ
		V <sub>GS</sub> =-1.5V, I <sub>D</sub> =-4A	22.6	28		mΩ
		V <sub>GS</sub> =-1.2V, I <sub>D</sub> =-2A	27.7	36		mΩ
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> =-5V, I <sub>D</sub> =-8A	39	53		S
V <sub>SD</sub>	Diode Forward Voltage	I <sub>S</sub> =-1A, V <sub>GS</sub> =0V	-0.55	-1		V
I <sub>S</sub>	Maximum Body-Diode Continuous Current				-4	A
<b>DYNAMIC PARAMETERS</b>						
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =-4V, f=1MHz		1465		pF
C <sub>oss</sub>	Output Capacitance			345		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			235		pF
R <sub>g</sub>	Gate resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, f=1MHz	10			Ω
<b>SWITCHING PARAMETERS</b>						
Q <sub>g</sub>	Total Gate Charge	V <sub>GS</sub> =-4.5V, V <sub>DS</sub> =-4V, I <sub>D</sub> =-8A		12.5	18	nC
Q <sub>gs</sub>	Gate Source Charge			1.5		nC
Q <sub>gd</sub>	Gate Drain Charge			3		nC
t <sub>D(on)</sub>	Turn-On Delay Time	V <sub>GS</sub> =-4.5V, V <sub>DS</sub> =-4V, R <sub>L</sub> =0.5Ω, R <sub>GEN</sub> =3Ω	4			ns
t <sub>r</sub>	Turn-On Rise Time		28			ns
t <sub>D(off)</sub>	Turn-Off Delay Time		99			ns
t <sub>f</sub>	Turn-Off Fall Time		43			ns
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =-8A, dI/dt=100A/μs	23			ns
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge	I <sub>F</sub> =-8A, dI/dt=100A/μs	7			nC

A. The value of R<sub>θJA</sub> is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub>=25° C. The Power dissipation P<sub>DSM</sub> is based on R<sub>θJA</sub>, t ≤ 10s value and the maximum allowed junction temperature of 150° C. The value in any given application depends on the user's specific board design.

B. The power dissipation P<sub>D</sub> is based on T<sub>J(MAX)</sub>=150° C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Repetitive rating, pulse width limited by junction temperature T<sub>J(MAX)</sub>=150° C. Ratings are based on low frequency and duty cycles to keep initial T<sub>J</sub>=25° C.

D. The R<sub>θJA</sub> is the sum of the thermal impedance from junction to case R<sub>θJC</sub> and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of T<sub>J(MAX)</sub>=150° C. The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

H. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub>=25° C.

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

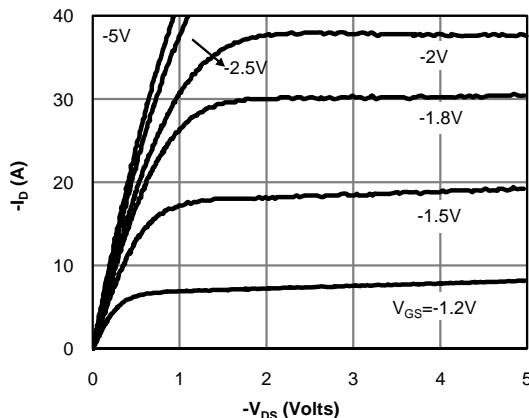


Fig 1: On-Region Characteristics (Note E)

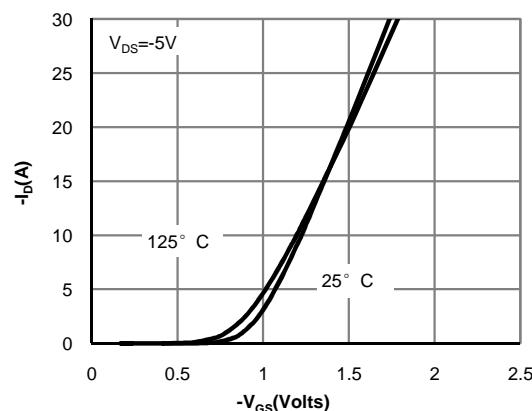


Figure 2: Transfer Characteristics (Note E)

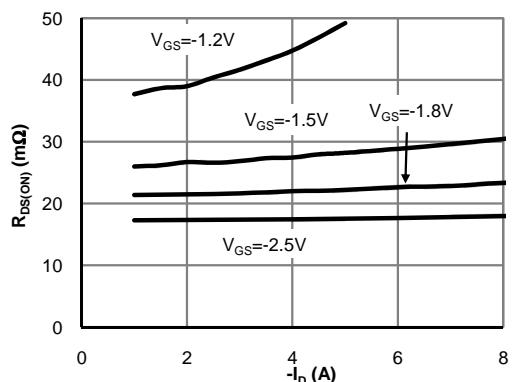


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

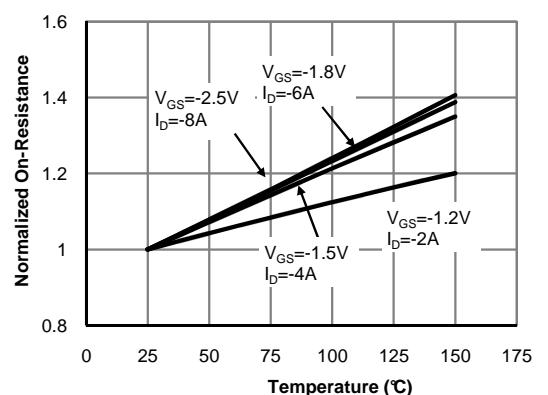


Figure 4: On-Resistance vs. Junction Temperature (Note E)

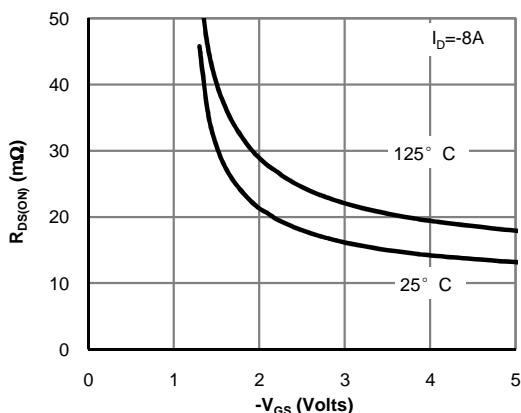


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

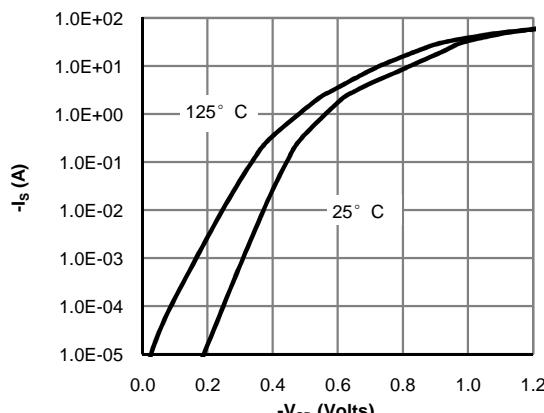
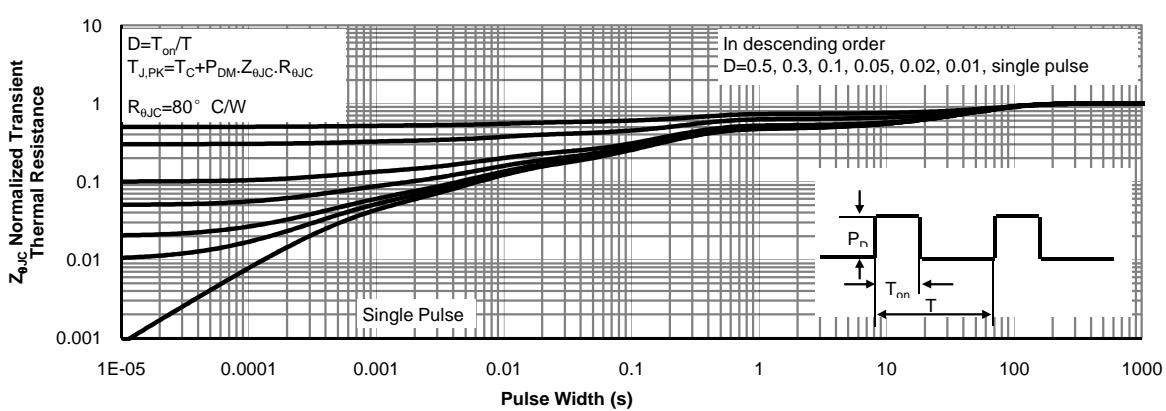
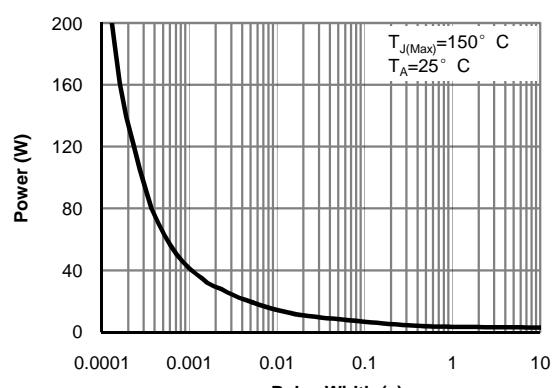
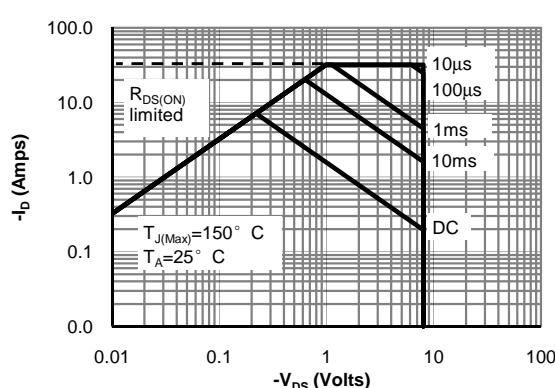
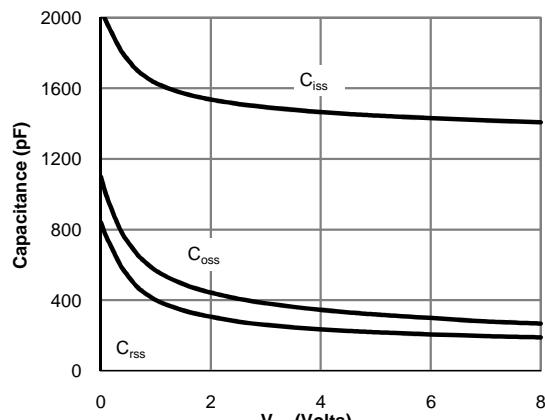
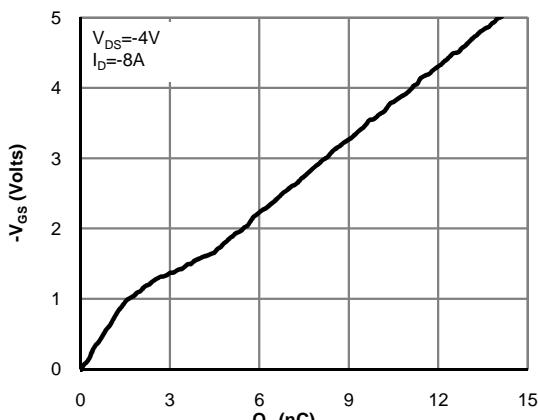
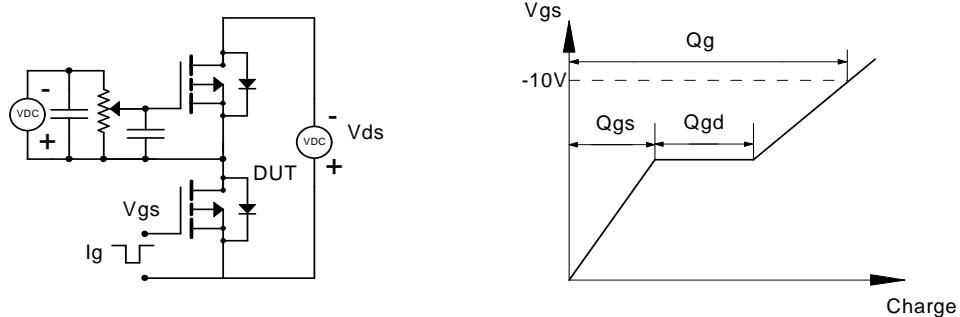


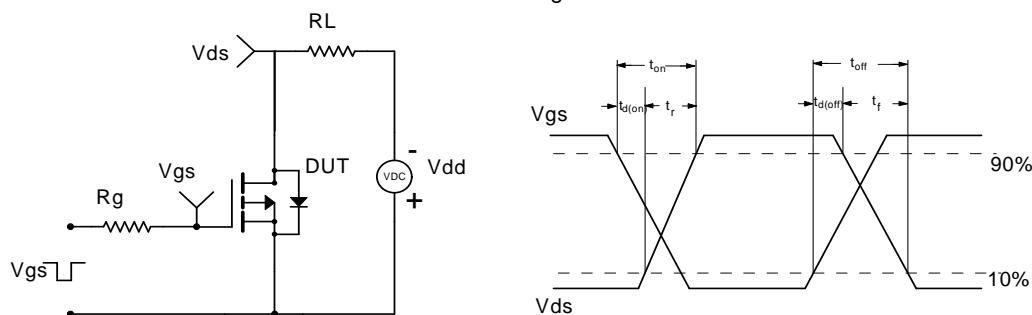
Figure 6: Body-Diode Characteristics (Note E)

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**


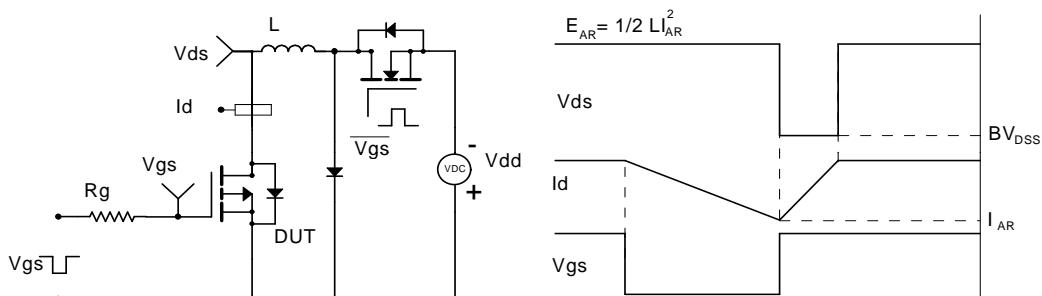
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

